

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2668	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:03
L2	2050	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:03
L3	1634	716/6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:03
L4	0	(716/4).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:12
L5	0	(716/4).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:12
L6	0	(716/5).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:12
L7	0	(716/6).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:13
L8	0	("716"/\$).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:13
L9	1	(partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:15

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L10	1	(702/181).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:25
L11	0	((partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:26
L12	0	((partition\$4 and (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:26
L13	1	((partition\$4 and (logic adj block\$2)) and ((multi\$3 adj cycle\$2) and (setup adj sequence\$2)) and (constraint adj set\$4)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:27
L14	1	(encod\$4) and ((scan adj cell) adj replac\$6) and (cost adj function) and (affinity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:31
L15	1	((encod\$4) and ((scan adj cell) adj replac\$6) and (cost adj function) and (affinity)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:31
L16	1	(select\$6) and (characterization) and ((scan adj cell\$2) adj replac\$6) and (cost adj function) and (affinity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:33
L17	1	((select\$6) and (characterization) and ((scan adj cell\$2) adj replac\$6) and (cost adj function) and (affinity)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:33

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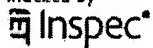
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Tip: Try removing quotes from your search to get more results.

Method and system for providing fast design for testability ...

... wherein the steps of determining the **cost function** and establishing the **affinity** ... one or more **scan cells** having the closest target characteristics

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A Partition-Based Approach for Identifying Failing **Scan Cells** in Scan-BIST with ... **cost function**-driven high-level synthesis, such that on-line testing ...

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